Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/071,174	REED ET AL.	
Examiner	Art Unit	
Jon Eric Angell	1635	

SEARCHED					
Class	Subclass	Date	Examiner		
536	23.1, 24.33	6/8/2005	JEA		
536	24.3+	6/8/2005	JEA		
435	320.1 325	6/8/2005	JEA		
435	252.3	6/8/2005	JEA		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
			ē		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STN EAST Inventor Name searched STIC SEQ search: SEQs 1, 2, 37 including alignment of 1 and 37 Reviewed and Updated	6/8/2005	JEA